**Product data sheet** 

# 1. General description

WeEnPACK-B1 module with WeEn 1200V Gen2 SiC MOSFET and PressFit pin type. Intergrated with NTC temperature sensor.





# 2. Features and benefits

- · Half bridge topology
- PressFit pins technology
- Low R<sub>DSon</sub>
- Low Switching Losses
- Low Q<sub>g</sub> and C<sub>rss</sub>
- Low Inductive Design

# 3. Applications

- Power inverters
- AC-DC converters
- DC-DC converters
- · Active power factor correctors
- Motor drivers

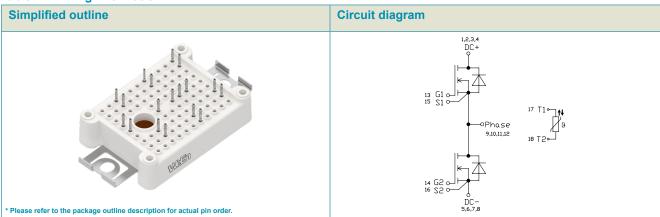
## 4. Quick reference data

#### Table 1. Quick reference data

| Symbol              | Parameter                        | Conditions  | Notes | Values     |      |     | Unit |  |  |
|---------------------|----------------------------------|---|-------|------------|------|-----|------|--|--|
| Absolute            | Absolute maximum rating          |   |       |            |      |     |      |  |  |
| V <sub>DS</sub>     | drain-source voltage             | T <sub>j</sub> = 25 °C  |       |            | 1200 |     | V    |  |  |
| I <sub>D</sub>      | drain current                    | V <sub>GS</sub> = 18 V; T <sub>h</sub> = 25 °C  |       |            | 53   |     | Α    |  |  |
| P <sub>tot</sub>    | total power dissipation          | T <sub>h</sub> = 25 °C  |       |            | 111  |     | W    |  |  |
| T <sub>j</sub>      | junction temperature             |   |       | -40 to 150 |      | °C  |      |  |  |
| Symbol              | Parameter                        | Conditions  | Notes | Min        | Тур  | Max | Unit |  |  |
| Static ch           | aracteristics                    |   | ,     |            |      |     |      |  |  |
| R <sub>DS(on)</sub> | drain-source on-state resistance | $V_{GS} = 15 \text{ V}; I_D = 45 \text{ A}; T_j = 25 \text{ °C}$                            |       | -          | 30   | -   | mΩ   |  |  |
|                     |                                  | V <sub>GS</sub> = 18 V; I <sub>D</sub> = 45 A; T <sub>j</sub> = 25 °C                       |       | -          | 24   | -   | mΩ   |  |  |
| Dynamic             | characteristics                  |   |       |            |      |     |      |  |  |
| Q <sub>G(tot)</sub> | total gate charge                | $I_D = 45 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$           |       | -          | 162  | -   | nC   |  |  |
| $Q_{GD}$            | gate-drain charge                | T <sub>j</sub> = 25 °C  |       | -          | 26   | -   | nC   |  |  |
| Source-d            | rain diode                       |   | 1     |            |      |     |      |  |  |
| Q <sub>r</sub>      | recovered charge                 | $I_{SD}$ = 45 A; $V_{GS}$ = -4 V; di/dt = 8500 A/ $\mu$ s; $V_{R}$ = 600 V; $T_{j}$ = 25 °C |       | -          | 592  | -   | nC   |  |  |

# 5. Pinning information

### **Table 2. Pinning information**



# 6. Ordering information

## **Table 3. Ordering information**

| Type number   | Package<br>Name | Orderable part number | Packing method | Small packing quantity | Package version      | Package issue date |
|---------------|-----------------|-----------------------|----------------|------------------------|----------------------|--------------------|
| WMSC030H12B1P | WeEnPACK-B1     | WMSC030H12B1P6T       | Tray           | 16                     | WeEnPACK-<br>B1PHB-A | 14-Dec-2023        |

# 7. Marking

# Table 4. Marking codes

| Type number   | Marking codes |
|---------------|---------------|
| WMSC030H12B1P | WMSC030H12B1P |

# 8. Limiting values

### **Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol                | Parameter                                  | Conditions  | Notes  | Values     | Unit |
|-----------------------|--|---|--------|------------|------|
| $T_{\text{stg}}$      | storage temperature                        |   |        | -40 to 150 | °C   |
| $T_{j.op}$            | operating junction temperature             |   |        | -40 to 150 | °C   |
| V <sub>ISOL</sub>     | RMS isolation voltage                      | T <sub>j</sub> = 25 °C; all terminals shorted;<br>f = 50 Hz; t = 1 s              |        | 3500       | V    |
| MOSFET                |  |   |        |            |      |
| V <sub>DS</sub>       | drain-source voltage                       | T <sub>j</sub> = 25 °C  |        | 1200       | V    |
| $V_{\rm GS,max}$      | gate-source voltage                        | Absolute maximum values   |        | -12 to 24  | V    |
| $V_{GS,op}$           | gate-source voltage                        | Recommended operational values  |        | -4 to 18   | V    |
| P <sub>tot</sub>      | total power dissipation                    | T <sub>h</sub> = 25 °C  |        | 111        | W    |
| I <sub>D</sub>        | drain current                              | V <sub>GS</sub> = 18 V; T <sub>h</sub> = 25 °C                                    |        | 53         | Α    |
|                       |  | V <sub>GS</sub> = 18 V; T <sub>h</sub> = 100 °C                                   |        | 33         | Α    |
| I <sub>DM</sub>       | peak drain current                         | pulse width t <sub>p</sub> limited by T <sub>jmax</sub>                           | Fig.17 | 100        | Α    |
| E <sub>as</sub>       | single pulse drain-to-<br>source avalanche | $I_{AS}$ = 15 A; L = 1 mH; $V_{DD}$ = 100 V;<br>$T_{j(init)}$ = 25 °C; per MOSFET |        | 112.5      | mJ   |
| Body Diod             | e  |   |        |            |      |
| I <sub>SD</sub>       | DC body diode forward current              | V <sub>GS</sub> = -4 V; T <sub>h</sub> = 25 °C                                    |        | 25         | А    |
| I <sub>SD,pulse</sub> | Pulse body diode current                   | verified by design, $t_p$ limited by $T_{jmax}$                                   |        | 100        | Α    |

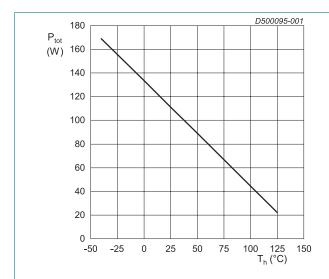


Fig. 1. Power dissipation as a function of heatsink temperature; maximum values

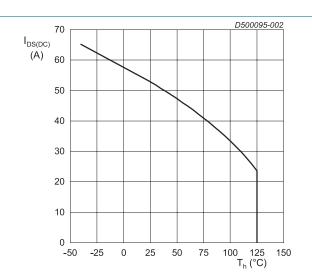


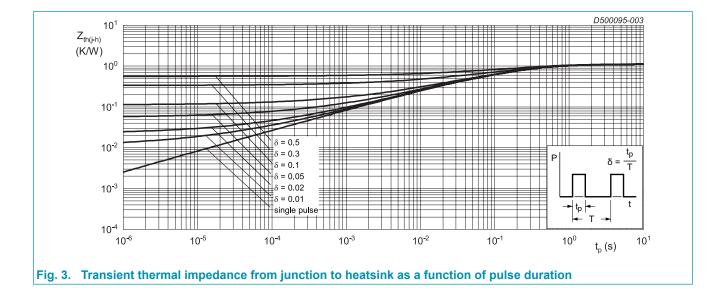
Fig. 2. Continuous Drain Current as a function of heatsink temperature

# 9. Thermal characteristics

**Table 6. Thermal characteristics** 

| Symbol               | Parameter  | Conditions                                  | Notes | Min   | Тур  | Max | Unit |
|----------------------|--|---|-------|-------|------|-----|------|
| R <sub>th(j-c)</sub> | thermal resistance from junction to case           | per MOSFET                                  |       | -     | 0.46 | -   | K/W  |
| R <sub>th(j-h)</sub> | thermal resistance<br>from junction to<br>heatsink | per MOSFET, λ <sub>grease</sub> = 1 W/(m·K) |       | -     | 1.12 | -   | K/W  |
| Internal Is          | solation   | basic insulation (class 1, IEC 61140)       |       | Al2O3 |      |     |      |
| d <sub>Creep</sub>   | Creepage distance                                  | terminal to heatsink                        |       | -     | 11.5 | -   | mm   |
|                      |  | terminal to terminal                        |       | -     | 6.3  | -   | mm   |
| d <sub>Clear</sub>   | Clearance  | terminal to heatsink                        |       | -     | 10   | -   | mm   |
|                      |  | terminal to terminal                        |       | -     | 5    | -   | mm   |
| СТІ                  | Comperative tracking index                         |   |       |       | >200 |     |      |
| F                    | Mounting force per clamp                           |   |       | 20    | -    | 50  | N    |
| G                    | Approximate Weight                                 |   |       | -     | 20   | -   | g    |

Note: Module is ESD sensitive. Handling precautions are recommanded.

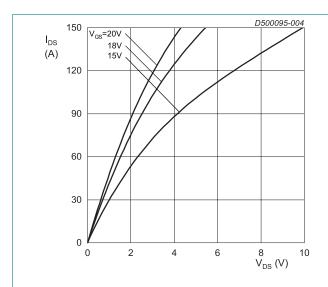


# 10. Characteristics

### **Table 7. Characteristics**

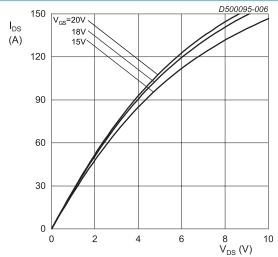
| MOSFET              |                                | 0   | Nata  | B.41: | T    | 8.0 | Hart |
|---------------------|--------------------------------|---|-------|-------|------|-----|------|
| Symbol              | Parameter                      | Conditions  | Notes | Min   | Тур  | Max | Unit |
|                     | aracteristics                  | T   | 1     | I     |      | 1   | 1    |
| $V_{(BR)DSS}$       | drain-source breakdown voltage | $I_D = 200 \mu A; V_{GS} = 0 V; T_j = 25 °C$                                      |       | 1200  | -    | -   | V    |
| $V_{GS(th)}$        | gate-source threshold voltage  | $I_D = 12 \text{ mA}; V_{DS} = 10 \text{ V}; T_j = 25 \text{ °C}$                 |       | 1.9   | 2.5  | 3.5 | V    |
| I <sub>DSS</sub>    | drain leakage current          | V <sub>DS</sub> = 1200 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C           |       | -     | 0.4  | 200 | μA   |
| I <sub>GSS</sub>    | gate leakage current           | V <sub>GS</sub> = 24 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C             |       | -     | 20   | 200 | nA   |
|                     | (absolute value)               | V <sub>GS</sub> = -12 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C            |       | -     | 20   | 200 | nA   |
| R <sub>DS(on)</sub> | drain-source on-state          | V <sub>GS</sub> = 15 V; I <sub>D</sub> = 45 A; T <sub>j</sub> = 25 °C             |       | -     | 30   | -   | mΩ   |
|                     | resistance                     | V <sub>GS</sub> = 18 V; I <sub>D</sub> = 45 A; T <sub>j</sub> = 25 °C             |       | -     | 24   | -   | mΩ   |
|                     |                                | V <sub>GS</sub> = 18 V; I <sub>D</sub> = 45 A; T <sub>j</sub> = 125 °C            |       | -     | 35.2 | -   | mΩ   |
|                     |                                | V <sub>GS</sub> = 18 V; I <sub>D</sub> = 45 A; T <sub>j</sub> = 150 °C            |       | -     | 39.8 | -   | mΩ   |
| $R_G$               | gate resistance,<br>each side  | $f$ = 1 MHz; $T_j$ = 25 °C, each die with 4.7 Ω $R_{G(ext)}$ in series            |       | -     | 3.5  | -   | Ω    |
| g <sub>fs</sub>     | transconductance               | V <sub>DS</sub> = 20 V; I <sub>D</sub> = 45 A; T <sub>j</sub> = 25 °C             |       | -     | 27   | -   | S    |
| Dynamic             | characteristics                |   |       |       |      |     |      |
| Q <sub>G(tot)</sub> | total gate charge              | $I_D = 45 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$ |       | -     | 162  | -   | nC   |
| Q <sub>GS</sub>     | gate-source charge             | T <sub>j</sub> = 25 °C  |       | -     | 65   | -   | nC   |
| $Q_{GD}$            | gate-drain charge              |   |       | -     | 26   | -   | nC   |
| C <sub>iss</sub>    | input capacitance              | V <sub>DS</sub> = 1000 V; V <sub>GS</sub> = 0 V; f = 1 MHz;                       |       | -     | 3.5  | -   | nF   |
| C <sub>oss</sub>    | output capacitance             | $T_j = 25 ^{\circ}\text{C}$   |       | -     | 172  | -   | pF   |
| C <sub>rss</sub>    | reverse transfer capacitance   |   |       | -     | 19   | -   | pF   |
| E <sub>oss</sub>    | Coss stored energy             |   |       | -     | 86   | -   | μJ   |
| t <sub>d(on)</sub>  | turn-on delay time             | V <sub>DS</sub> = 800 V; V <sub>GS</sub> = -4 V/18 V;                             |       | -     | 16   | -   | ns   |
| t <sub>r</sub>      | rise time                      | $R_{G(ext)}$ = 2.4 Ω; $I_D$ = 45 A; L = 100 μH; $T_i$ = 25 °C                     |       | -     | 8    | -   | ns   |
| $t_{\text{d(off)}}$ | turn-off delay time            | ,   |       | -     | 48   | -   | ns   |
| t <sub>f</sub>      | fall time                      |   |       | -     | 18   | -   | ns   |
| E <sub>on</sub>     | turn-on energy                 |   |       | -     | 616  | -   | μJ   |
| E <sub>off</sub>    | turn-off energy                | 1   |       | -     | 376  | -   | μJ   |

| Body dio           | de                            |  |       |        |      |     |      |
|--------------------|-------------------------------|--|-------|--------|------|-----|------|
| Symbol             | Parameter                     | Conditions   | Notes | Min    | Тур  | Max | Unit |
| Static ch          | aracteristics                 |  | ,     |        |      |     |      |
| $V_{SD}$           | source-drain voltage          | $V_{GS} = -4 \text{ V}; I_{SD} = 45 \text{ A}; T_j = 25 \text{ °C}$                            |       | -      | 5.8  | -   | V    |
|                    |                               | $V_{GS}$ = -4 V; $I_{SD}$ = 45 A; $T_{j}$ = 150 °C   |       | -      | 5.1  | -   | V    |
| Dynamic            | characteristics               |  | ,     |        | '    |     |      |
| t <sub>rr</sub>    | reverse recovery time         | $I_{SD} = 45 \text{ A}; \ V_{GS} = -4 \text{ V}; \ \text{di/dt} = 8500 \text{ A/}\mu\text{s};$ |       | -      | 17   | -   | ns   |
| Q <sub>r</sub>     | recovered charge              | $V_R = 600 \text{ V}; T_j = 25 ^{\circ}\text{C}$   |       | -      | 592  | -   | nC   |
| I <sub>rrm</sub>   | reverse recovery current      |  |       | -      | 58   | -   | Α    |
| E <sub>rec</sub>   | reverse recovery energy       |  |       | -      | 312  | -   | μJ   |
| t <sub>rr</sub>    | reverse recovery time         | $I_{SD}$ = 45 A; $V_{GS}$ = -4 V; di/dt = 10500 A/ $\mu$ s;                                    |       | -      | 21   | -   | ns   |
| Q <sub>r</sub>     | recovered charge              | V <sub>R</sub> = 600 V; T <sub>j</sub> = 150 °C  |       | -      | 1350 | -   | nC   |
| I <sub>rrm</sub>   | reverse recovery current      |  |       | -      | 100  | -   | Α    |
| E <sub>rec</sub>   | reverse recovery energy       |  |       | -      | 860  | -   | μJ   |
| NTC ther           | mistor                        |  |       |        |      |     |      |
| Symbol             | Parameter                     | Conditions   | Notes | Min    | Тур  | Max | Unit |
| R <sub>25</sub>    | Rated resistance              | T <sub>NTC</sub> = 25 °C   |       | -      | 5000 | -   | Ω    |
| R <sub>100</sub>   |                               | T <sub>NTC</sub> = 100 °C  |       | 465±5% |      | )   | Ω    |
| B <sub>25/50</sub> | B-value                       | $R_2 = R_{25} \exp[B_{25/50}(1/T_2 - 1/(298.15K))]$  |       |        | 3380 |     | K    |
|                    | Maximum operating temperature |  |       | -      | 200  | -   | °C   |
|                    | Dissipation costant           |  |       | -      | 2    | -   | mW/K |
|                    | Thermal time constant         |  |       | -      | ≤10  | -   | s    |

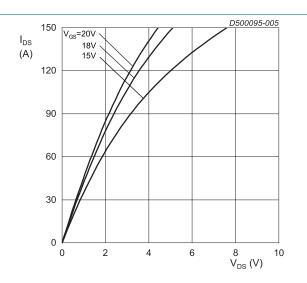


 $T_i = -40 \, ^{\circ}\text{C}; t_p < 200 \, \mu\text{s}$ 

Fig. 4. Output characteristics; drain current as a function of drain-source voltage; typical values

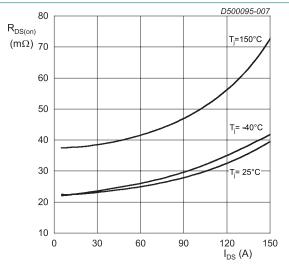


 $T_i = 150 \, ^{\circ}\text{C}; t_p < 200 \, \mu\text{s}$ Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values



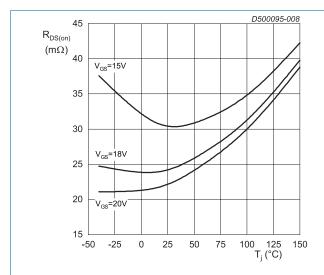
 $T_i = 25 \, ^{\circ}C; t_p < 200 \, \mu s$ 

Fig. 5. Output characteristics; drain current as a function of drain-source voltage; typical values



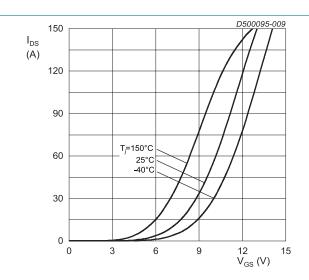
 $V_{GS} = 18 \text{ V}; t_p < 200 \mu \text{s}$ 

Fig. 7. Drain-source on-state resistance as a function of drain current; typical values



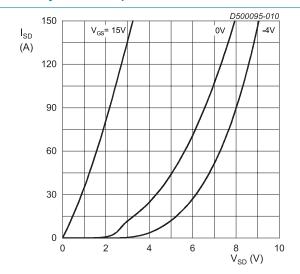
 $I_{DS} = 45 \text{ A}; t_p < 200 \text{ }\mu\text{s}$ 

Fig. 8. Drain-source on-state resistance as a function of junction temperature



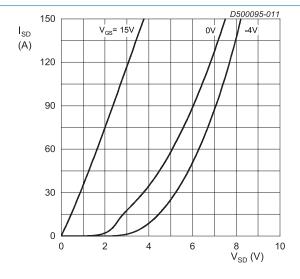
 $V_{DS} = 20 \text{ V}; t_p < 200 \text{ }\mu\text{s}$ 

Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values



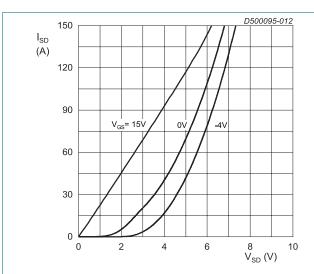
 $T_j = -40 \, ^{\circ}\text{C}; \, t_p < 200 \, \mu\text{s}$ 

Fig. 10. Body diode forward characteristics; typical values



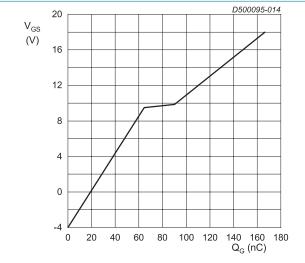
 $T_j = 25 \, ^{\circ}C; t_p < 200 \, \mu s$ 

Fig. 11. Body diode forward characteristics; typical values

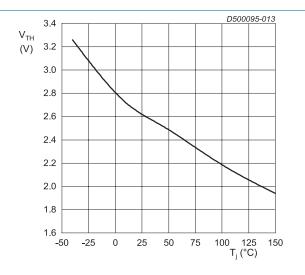


 $T_j = 150 \, ^{\circ}\text{C}; t_p < 200 \, \mu\text{s}$ 

Fig. 12. Body diode forward characteristics; typical values



 $I_{DS}$  = 45 A;  $I_{GS}$  = 0.1 mA;  $V_{DS}$  = 800 V;  $T_j$  = 25 °C Fig. 14. Gate-source voltage as a function of gate charge; typical values



 $V_{DS}$  = 10 V;  $I_{DS}$  = 12 mA Fig. 13. Threshold voltage as a function of junction

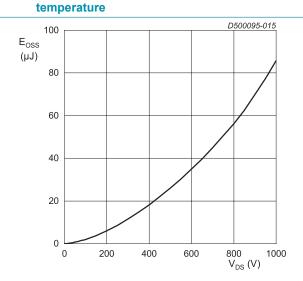
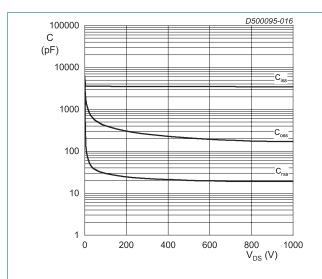


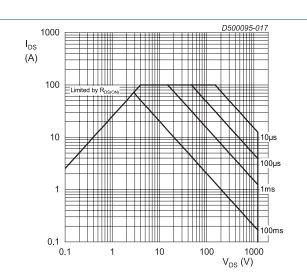
Fig. 15. Output capacitor stored energy as a function of drain-source voltage



 $V_{DS} = 0 - 1000 V$  $T_i = 25 \, ^{\circ}\text{C}; \, V_{AC} = 25 \, \text{mV}; \, f = 1 \, \text{MHz}$ 

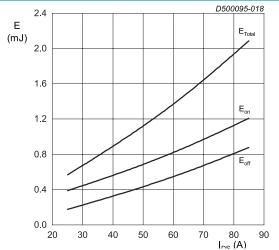
values

Fig. 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical

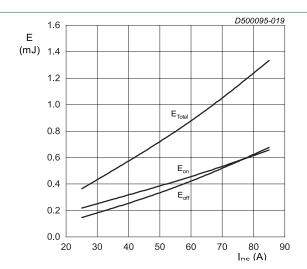


 $T_i = 25 \, ^{\circ}C; D = 0$ Parameter: t<sub>p</sub>

Fig. 17. Forward bias safe operating area

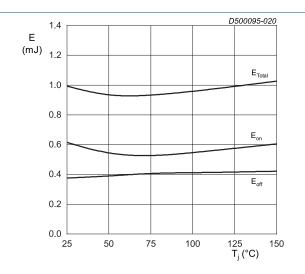


 $T_{j}$  = 25 °C;  $V_{DD}$  = 800 V;  $R_{G(ext)}$  = 2.4  $\Omega;$   $R_{G(on)}$  = 2.4  $\Omega;$   $V_{GS}$  = -4 V/18 V; L = 100  $\mu H$ Fig. 18. Clamped Inductive Switching Energy as a function of drain current



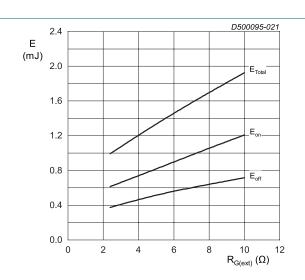
 $T_{j}$  = 25 °C;  $V_{DD}$  = 600 V;  $R_{G(off)}$  = 2.4  $\Omega;$   $R_{G(on)}$  = 2.4  $\Omega;$   $V_{GS}$  = -4 V/18 V; L = 100  $\mu H$ 

Fig. 19. Clamped Inductive Switching Energy as a function of drain current



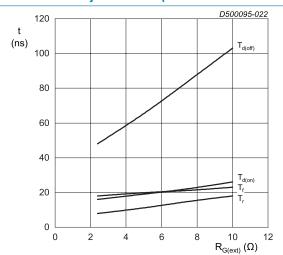
 $I_{DS}$  = 45 A;  $V_{DD}$  = 800 V;  $R_{G(off)}$  = 2.4  $\Omega;$   $R_{G(on)}$  = 2.4  $\Omega;$   $V_{GS}$  = -4 V/18 V; L = 100  $\mu H$ 

Fig. 20. Clamped Inductive Switching Energy as a function of junction temperature



 $T_{\rm j}$  = 25 °C;  $V_{\rm DD}$  = 800 V;  $I_{\rm DS}$  = 45 A;  $V_{\rm GS}$  = -4 V/18 V; L = 100  $\mu H$ 

Fig. 21. Clamped Inductive Switching Energy as a function of external gate resistance



 $T_{j}$  = 25 °C;  $V_{DD}$  = 800 V;  $I_{DS}$  = 45 A;  $V_{GS}$  = -4 V/18 V; L = 100  $\mu H$ 

Fig. 22. Switching time as a function of external gate resistance

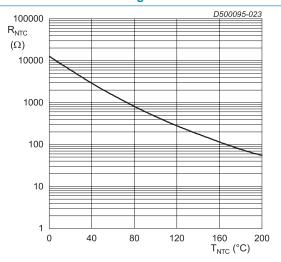
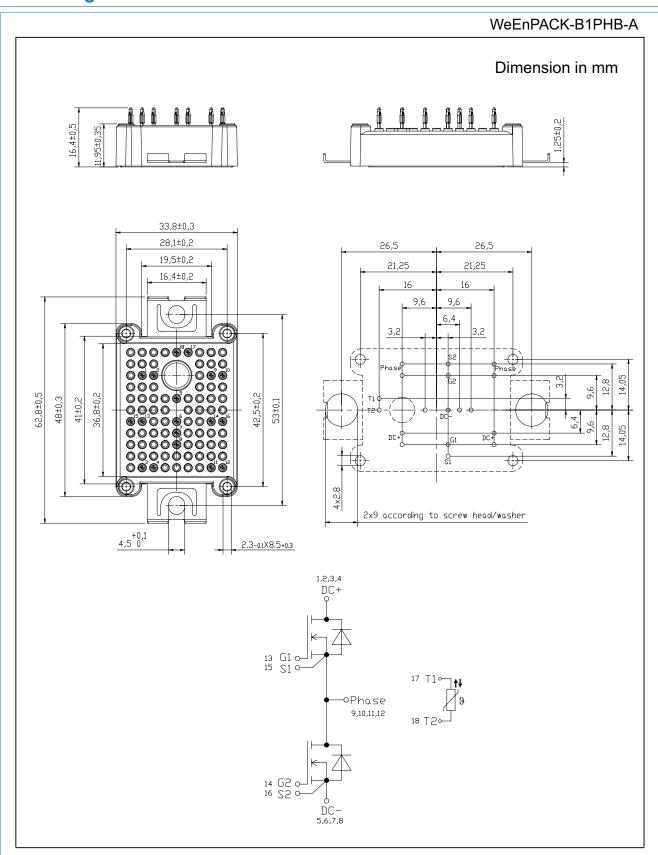


Fig. 23. NTC thermistor resistance as a function of NTC temperature

# 11. Package outline



# 12. Legal information

#### Data sheet status

| Document status [1][2]               | Product status [3] | Definition  |
|--------------------------------------|--------------------|---|
| Objective<br>[short] data<br>sheet   | Development        | This document contains data from the objective specification for product development. |
| Preliminary<br>[short] data<br>sheet | Qualification      | This document contains data from the preliminary specification.                       |
| Product<br>[short] data<br>sheet     | Production         | This document contains the product specification.                                     |

- Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
- The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <a href="http://www.ween-semi.com">http://www.ween-semi.com</a>.

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